Lecture 15

P-N Junction Diodes: Part 5

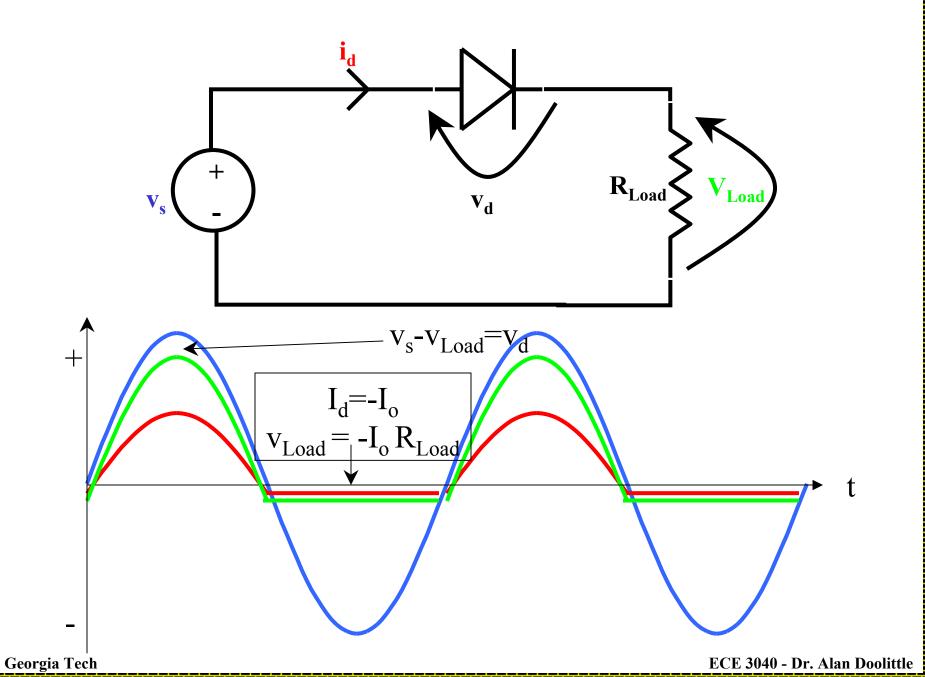
Large signal (complete model) and small signal (limited use) models of a Diode

Reading:

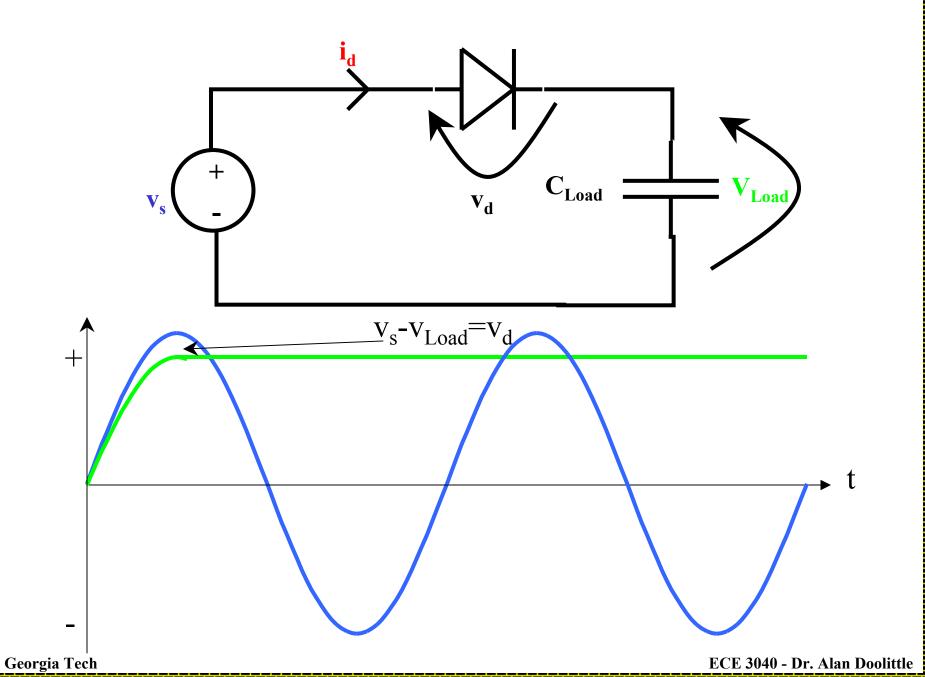
Jaeger 3.4-3.14, 13.4, Notes

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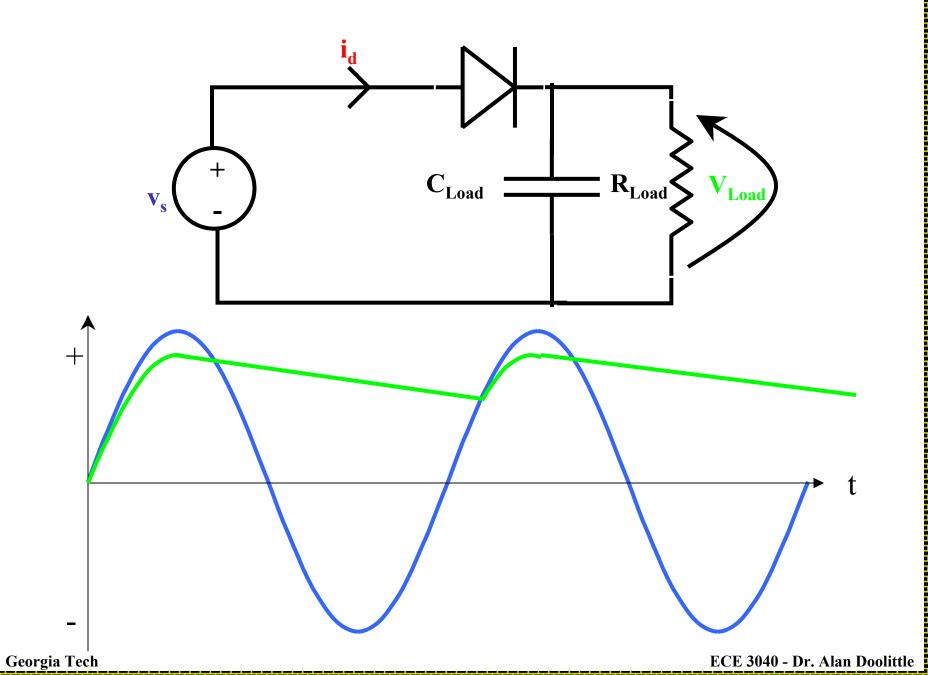
Diode Applications: 1/2 Wave Rectifier



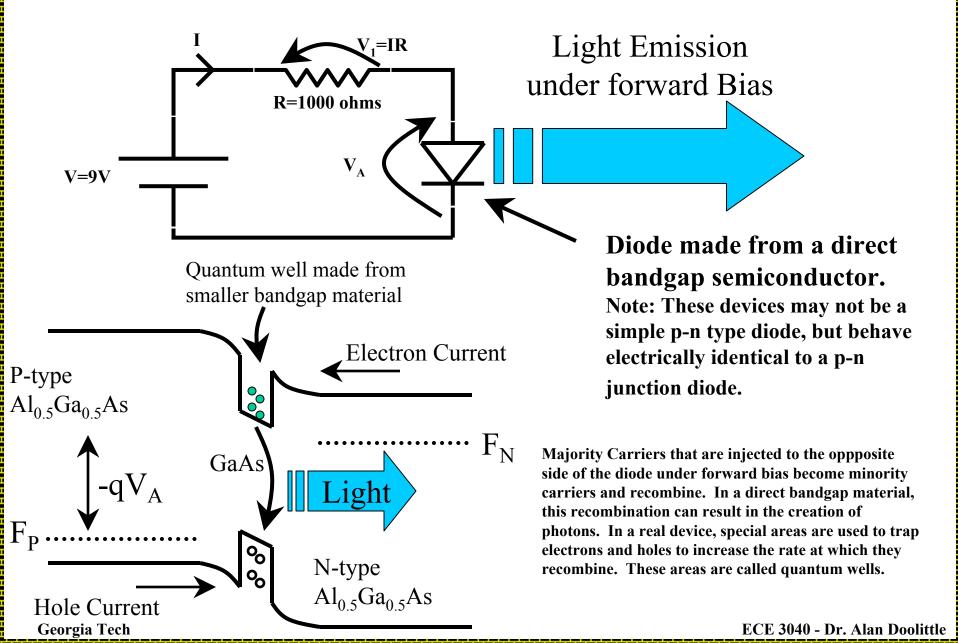
Diode Applications: Peak Detector



Diode Applications: 1/2 Wave Rectifier with an RC Load



Diode Applications: LED or a Laser Diode



Models used for analysis of Diode Circuits

Mathematical Model (previously developed) Graphical Analysis Ideal diode Model

•Treat the diode as an ideal switch Constant Voltage Drop Model

•Treat as an ideal switch plus a battery Large signal Model (model used by SPICE transient analysis)

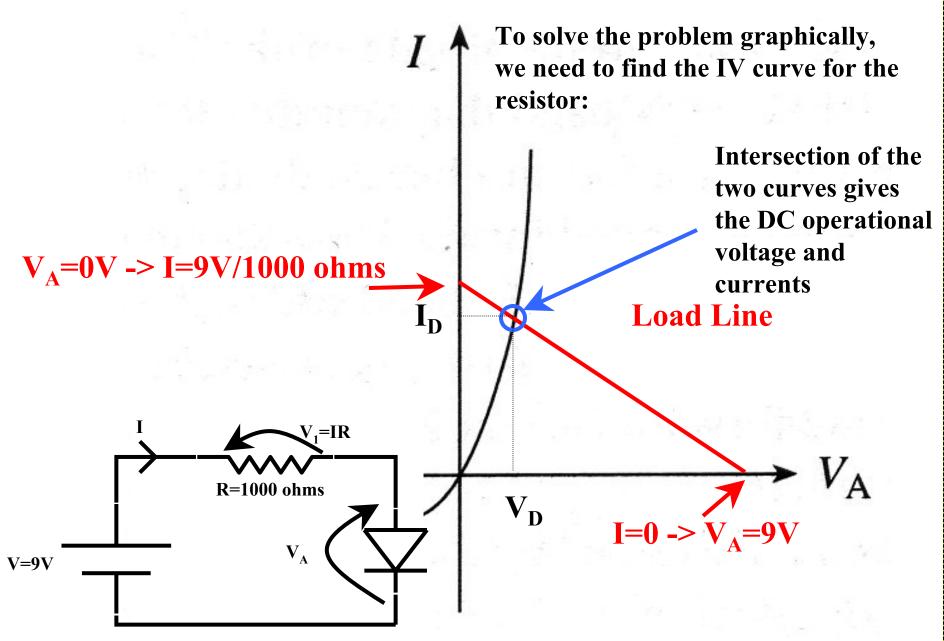
•multi-components

•generally applicable

Small Signal Model (model used by SPICE AC analysis) •easier math

•valid only for limited conditions-ie small signals

Diode Circuits: Graphical Solution



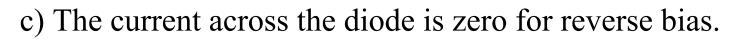
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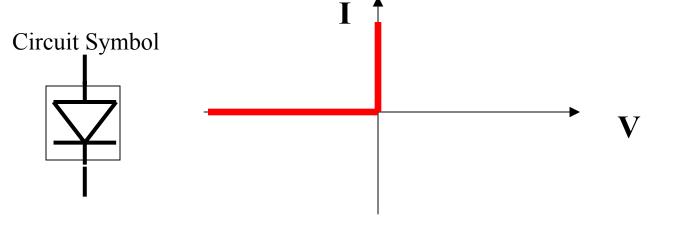
Diode Circuits: Other Models

Besides the direct mathematical solution and the graphical solution, we can use 2 other models to approximate circuit solutions:

- 1.) Ideal Diode Model:
 - a) The voltage across the diode is zero for forward bias.

b) The slope of the current voltage curve is infinite for forward bias.





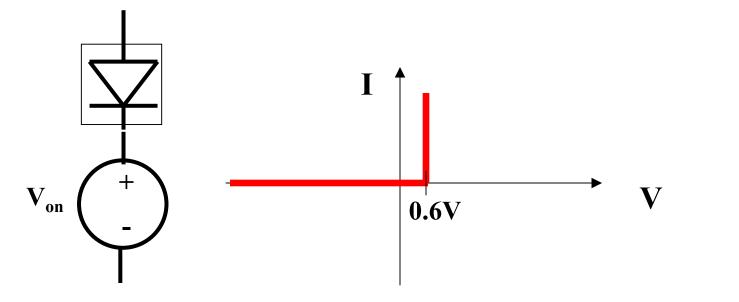
Diode Circuits: Other Models

2.) Constant Voltage Drop (CVD) Model:

a) The voltage across the diode is a non-zero value for forward bias. Normally this is taken as 0.6 or 0.7 volts.

b) The slope of the current voltage curve is infinite for forward bias.

c) The current across the diode is zero for reverse bias.



Concept of the Small- Signal Model

•Superposition principle allows us to separate DC and AC analysis of circuits containing active devices (like diodes, transistors, amplifiers etc...).

•We assume the AC signals are small enough so that the circuit behaves linearly and can be analyzed by replacing "non-linear" components by "Linear Elements" such as resistors etc...

•DC analysis is first performed to determine the bias point which will determine some of the parameters used in the "AC-small signal analysis".

•Consider a two terminal device (like a pn diode) at a given DC *operating point* (or "Q- point").

Let: $V_D = DC$ voltage applied to the diode $I_D = DC$ current produced by the diode Total current or voltage = DC part + AC part:

 $v_{D} = V_{D} + v_{d} \qquad i_{D} = I_{D} + i_{d}$ Note: (1) all caps = DC; (2) all lower case = AC; (3) lower case symbol with upper case subscript = total voltage or current Georgia Tech

Diode Biased in For small AC voltage Forward Bias: Tiny "swings", v_d , about a fixed small signal DC voltage, V_D the diode IV resistance, r_d. curve can be approximated as a resistor (I.e. linear currentvoltage relationship). The fixed DC operating point, $i_{D} = I_{D} + i_{d}$ LD $(V_{\rm D}-I_{\rm D})$, is called the bias point or the quiescent or Qpoint.

3

I_D

Diode Biased in

small signal

resistance, r_d.

Forward Bias: Tiny

 $i_{D} = I_{D} + i_{d}$

For small AC voltage "swings", v_d , about a fixed DC voltage, V_D the diode IV curve can be approximated as a resistor (I.e. linear currentvoltage relationship). The fixed DC operating point, (V_D-I_D) , is called the bias point or the quiescent or Qpoint.

3

Diode Biased in

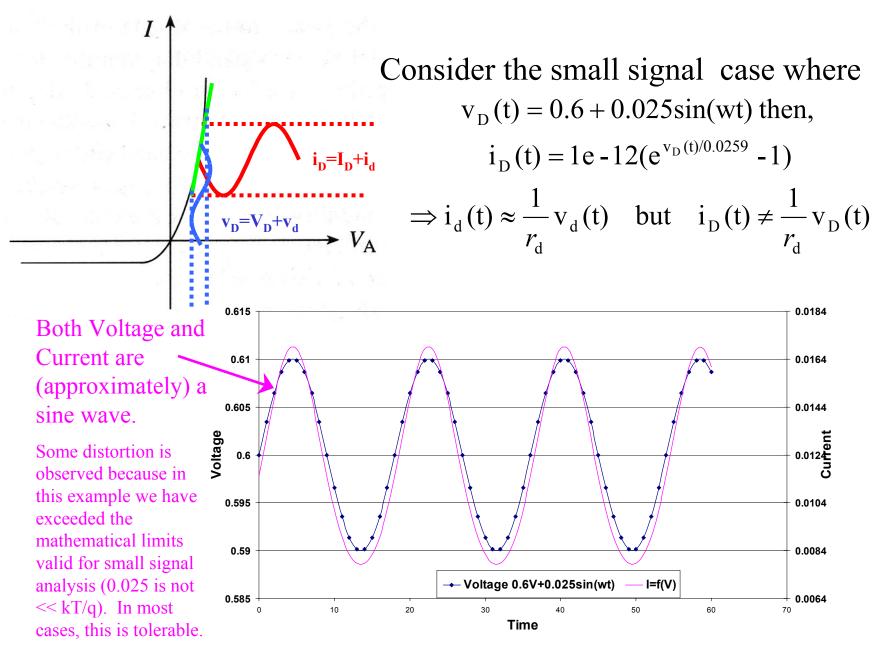
"small signal"

resistance, r_d.

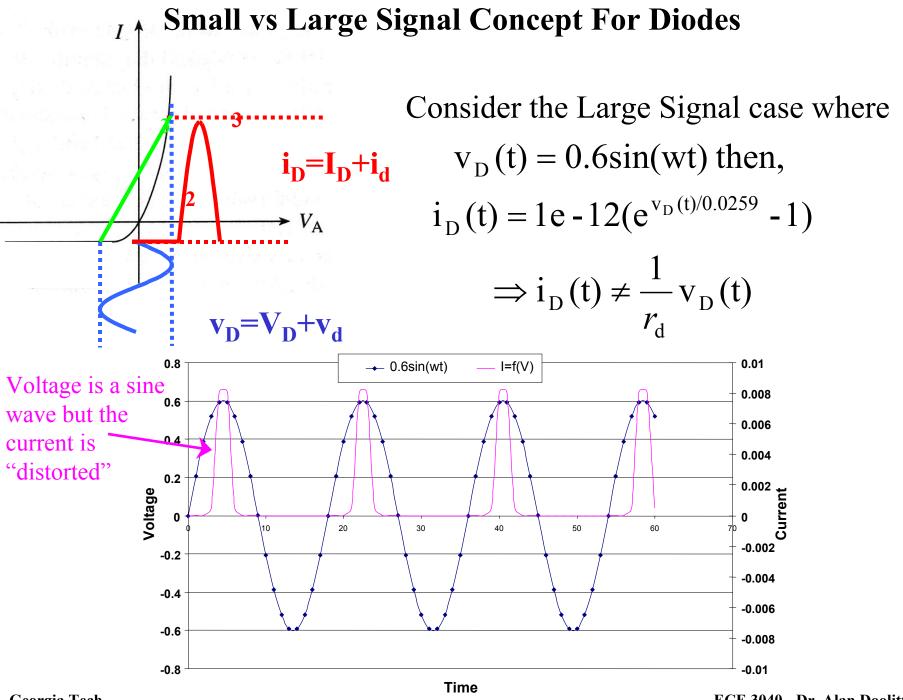
Forward Bias: Tiny

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Small vs Large Signal Concept For Diodes

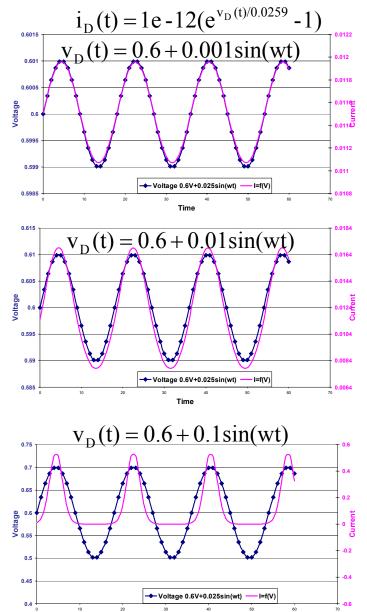


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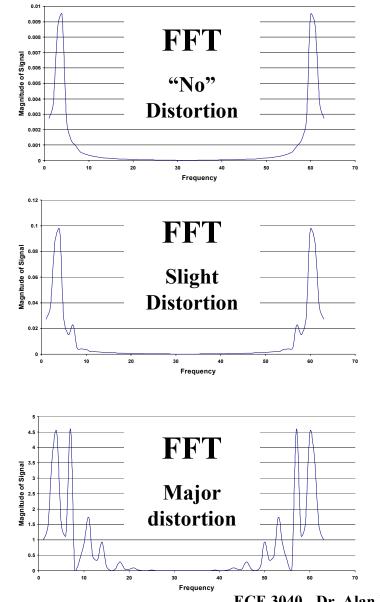


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The transition from valid small signal limits to Large Signal conditions is a matter of what is acceptable for your requirements



Time



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 $g_d \equiv small \ signal \ conduc \ tan \ ce \ of \ the \ diode$ $r_d \equiv small \ signal \ resis \ tan \ ce \ of \ the \ diode, \ r_d = - g_{d} = \frac{\partial i_{D}}{\partial v_{D}} \Big|_{Bias \ Po \ int \ or \ "Quiscient" \ or \ "Q-po \ int"}$ $= \frac{\partial \left\{ I_{S} \left(e^{\frac{v_{D}}{V_{T}}} - 1 \right) \right\}}{2} \Big|_{Q-point}$ $=\frac{I_{S}}{V_{-}}e^{\frac{v_{D}}{V_{T}}}\Big|_{Q-point}=\frac{I_{S}}{V}e^{\frac{V_{D}}{V_{T}}}e^{\frac{v_{d}}{V_{T}}}$ Assuming small signals, $v_d \langle \langle V_T, e^{v_d / V_T} \rightarrow 1$ and $=\frac{I_{s}e^{V_{D}/V_{T}}}{V_{T}}=\frac{I_{s}e^{V_{D}/V_{T}}-I_{s}+I_{s}}{V_{T}}$ $g_d = \frac{I_D + I_S}{V_T}$

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$$I_{D} = I_{o} \left(e^{V_{A}/V_{T}} - 1 \right) \text{ where } V_{T} = \frac{kT}{q}$$

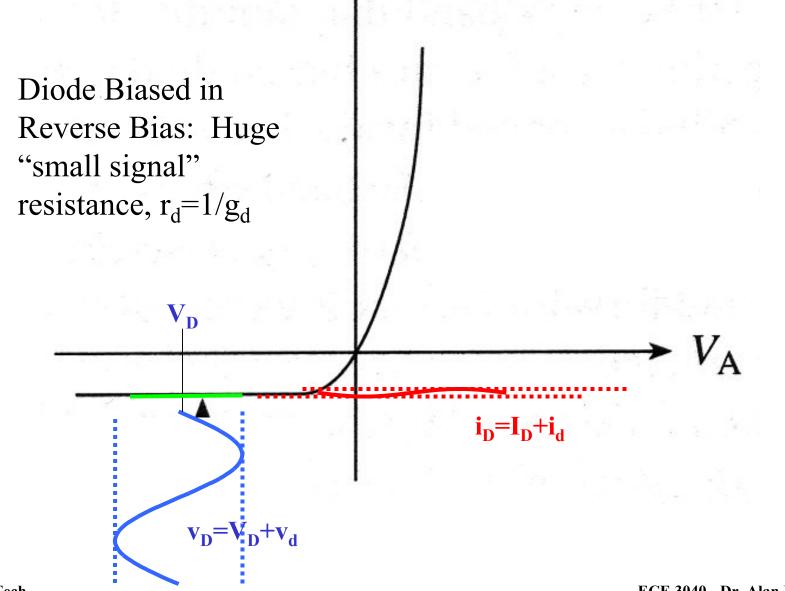
$$i_{D} = I_{D} + g_{d} V_{d}$$

$$g_{d} = \frac{I_{D} + I_{S}}{V_{T}} \text{ in General}$$

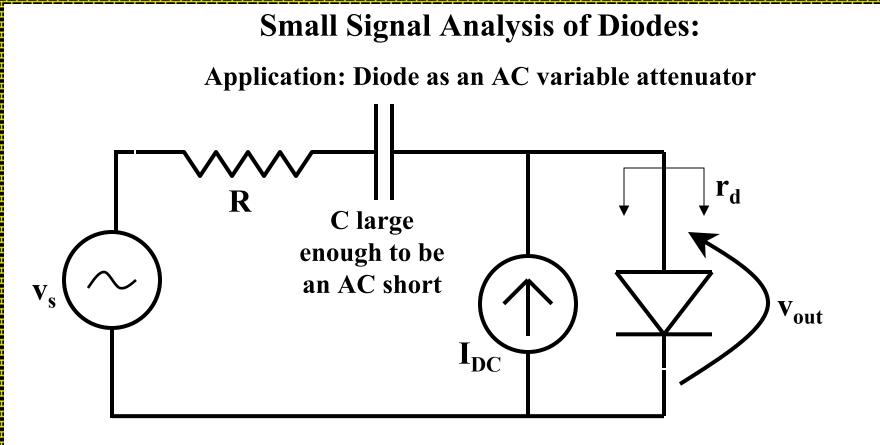
$$g_{d} \approx \frac{I_{D}}{V_{T}} \text{ in Forward Bias} \longrightarrow V_{A} >> 0 \rightarrow I_{D} \approx I_{o}e^{\frac{V_{A}}{V_{T}}} \text{ where } V_{T} = \frac{kT}{q}$$

$$g_{d} \approx \frac{-I_{S} + I_{S}}{V_{T}} \approx 0 \text{ in Reverse Bias} \longrightarrow V_{A} << 0 \rightarrow e^{\frac{V_{A}}{V_{T}}} \rightarrow 0$$

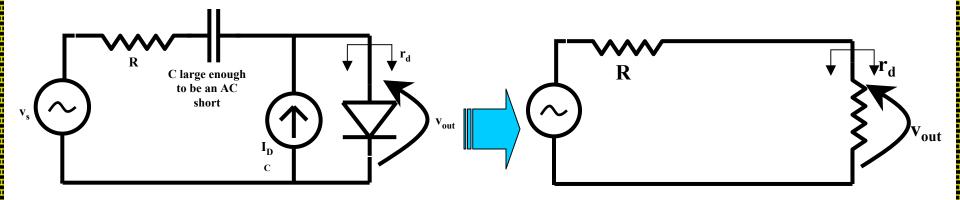
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Conversion to AC equivalent circuit

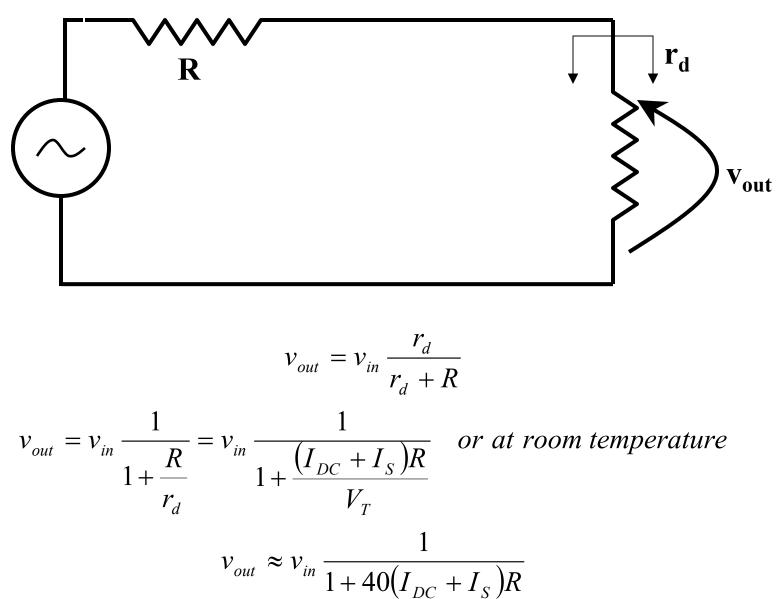


Steps to Analyze a Diode Circuit

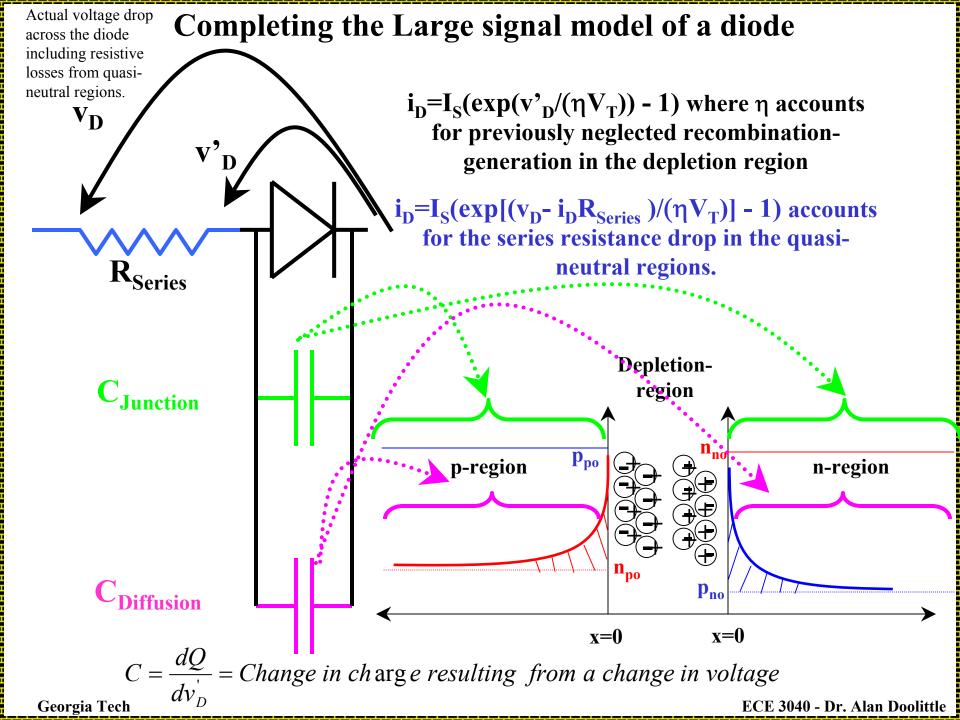
1.) Determine DC operating point and calculate small signal parameters, r_d and others to come in later lectures)

- 2.) Convert to the AC only model.
- •DC Voltage sources are shorts
- •DC Current sources are open circuits
- •Large capacitors are short circuits
- •Large inductors are open circuits

Application: Diode as an AC variable attenuator



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For an abrupt diode (uniform doping on both sides of the junction):

$$C_{junction} = \frac{K_s \varepsilon_o A}{W}$$

but...

$$W = x_p + x_n = \sqrt{\frac{2K_s \varepsilon_o}{q} \frac{(N_A + N_D)}{N_A N_D} (V_{bi} - V_A)}$$

$$C_{junction} = A \sqrt{\frac{qK_s \varepsilon_o}{2} \frac{N_A N_D}{(N_A + N_D)} \frac{1}{(V_{bi} - V_A)}}$$

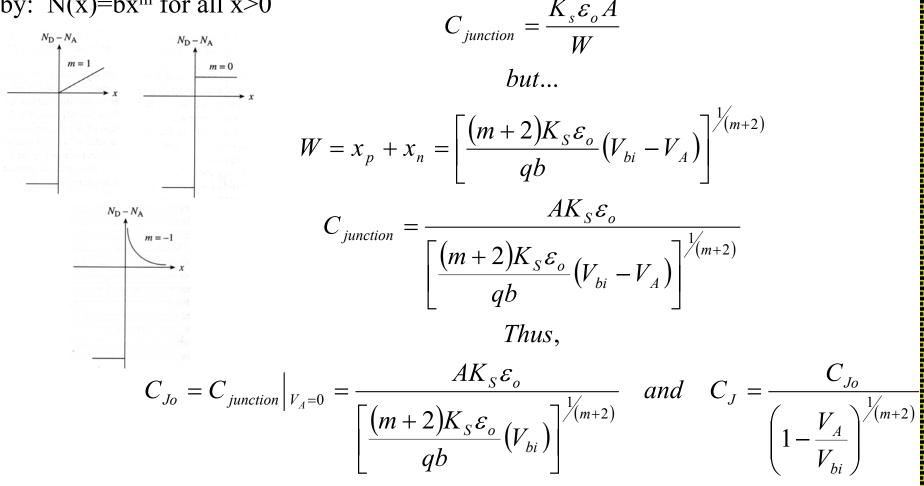
Thus,

$$C_{Jo} = C_{junction} \Big|_{V_A = 0} = A \sqrt{\frac{qK_s \varepsilon_o}{2} \frac{N_A N_D}{(N_A + N_D)} \frac{1}{(V_{bi})}} \quad and \quad C_J = \frac{C_{Jo}}{\sqrt{1 - \frac{V_A}{V_{bi}}}}$$

Junction capacitance is due to *majority carrier* charges displaced by the depletion width (I.e. similar to a parallel plate capacitor).

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More generally for a profile with a constant doping on the heavily doped side of the junction and variable doping profile on the a low doped side that is described by: $N(x)=bx^m$ for all x>0 $K_a \varepsilon_a A$



Junction capacitance is due to *majority carrier* charges displaced by the depletion width (I.e. similar to a parallel plate capacitor).

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$$C_{Diffusion} = \frac{dQ_D}{dv'_D}$$

$$= \frac{dQ_D}{dt} \frac{dt}{dv'_D}$$

$$Q_D = qA \int_0^\infty p_{no} \left(e^{\frac{v'_D}{V_T}} - 1 \right) e^{\frac{-x}{L_p}} dx + qA \int_0^\infty n_{po} \left(e^{\frac{v'_D}{V_T}} - 1 \right) e^{\frac{-x}{L_n}} dx$$

$$= \left(e^{\frac{v'_D}{V_T}} - 1 \right) \left[p_{no} L_p + n_{po} L_n \right] qA$$

$$\frac{dQ_D}{dt} = \frac{1}{V_T} \left(e^{\frac{v'_D}{V_T}} \right) \left[p_{no} L_p + n_{po} L_n \right] qA \frac{dv'_D}{dt}$$

$$\frac{dQ_D}{dt} = \frac{1}{V_T} \left[\frac{I_S \left(e^{\frac{v'_D}{V_T}} - 1 + 1 \right)}{I_S} \right] \left[p_{no} L_p + n_{po} L_n \right] qA \frac{dv'_D}{dt}$$

Diffusion capacitance due to "excess injected" <u>minority carrier</u> charge at the depletion region edges. Since this charge results from minority carriers, this capacitance is negligible at zero or reverse biases.

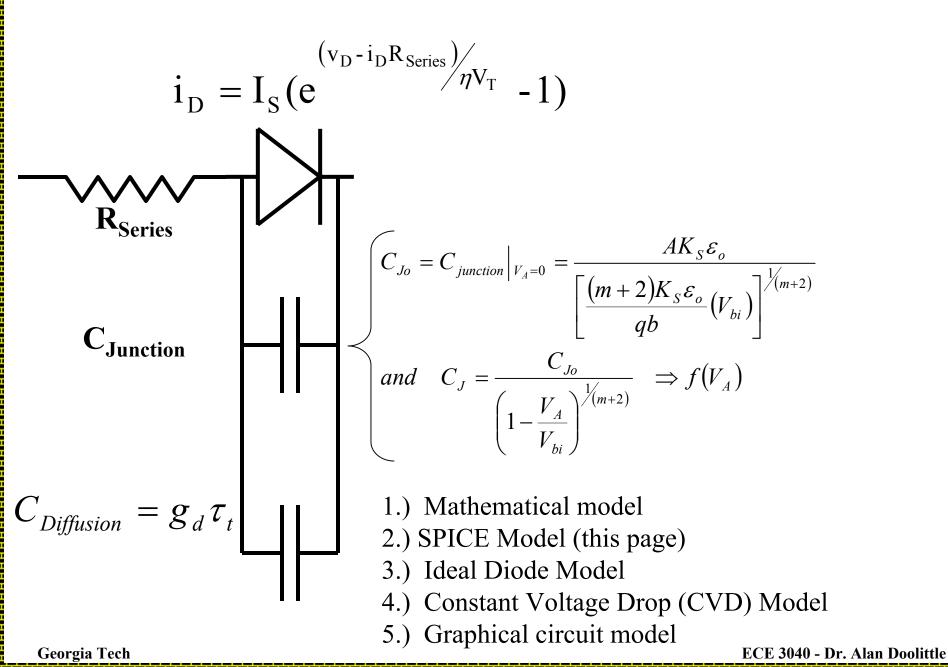
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 $C_{Diffusion} = g_d \tau_t$ where $\tau_t = \frac{\left[p_{no}L_p + n_{po}L_n\right]qA}{I_s}$ is the transit time or how quickly a carrier can respond

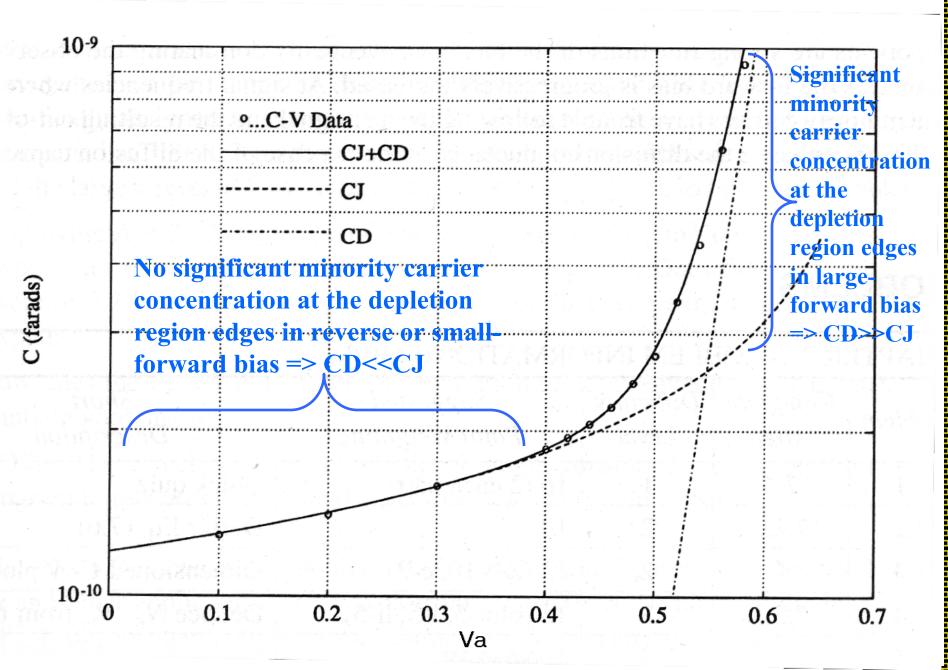
to a change in voltage (physically the carriers have to move across the junction, requiring a finite time to do so)

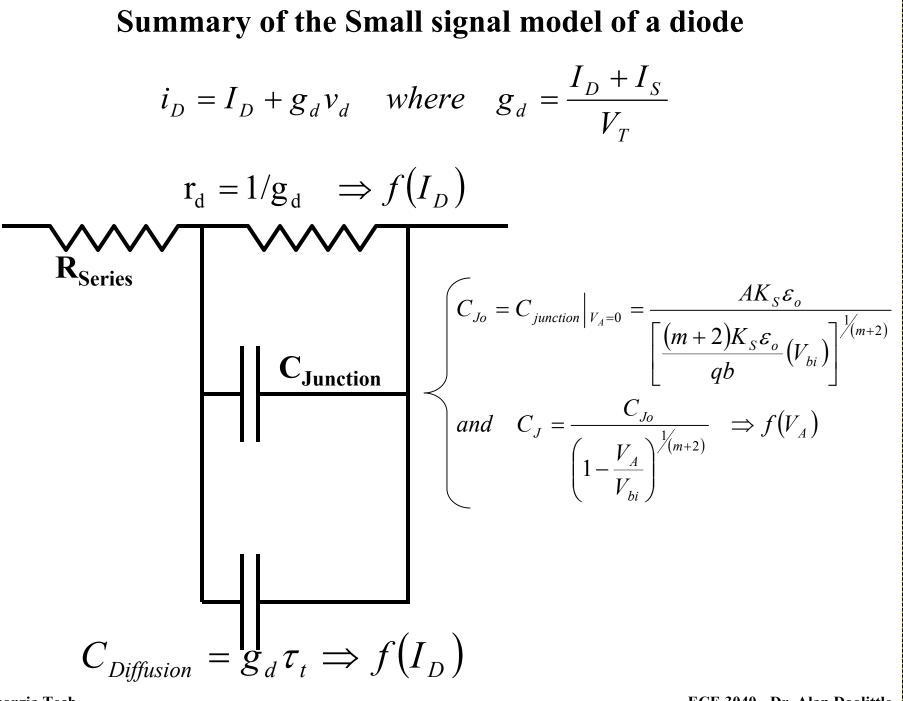
or in SPICE,
$$C_{Diffusion} = \frac{\partial i_D}{\partial v_D} \tau_t$$

Diffusion capacitance due to "excess injected" *minority carrier* charge at the depletion region edges. Georgia Tech ECE 3040 - Dr. Alan Doolittle Summary of the Large signal model of a diode (SPICE Model)



Addition of Capacitance Components





Things we have added to account for "Non-ideal" behavior

- •Series resistance to account for finite resistance of the quasi-neutral regions and metal contact resistance's.
- •Diode "ideality factor", η , to account for thermal recombinationgeneration in the depletion region.
- Junction capacitance due to majority carrier charges displaced by the depletion width (I.e. similar to a parallel plate capacitor).
 Diffusion capacitance due to "excess injected" minority carrier charge at the depletion region edges. Since this charge results from minority carriers, this capacitance is negligible at zero or reverse biases.

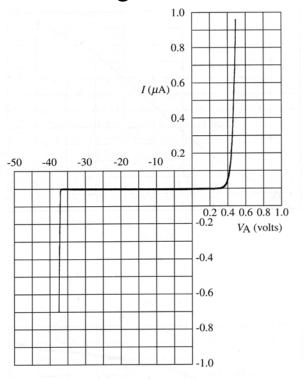
Things we still need to add to account for "Non-ideal" behavior

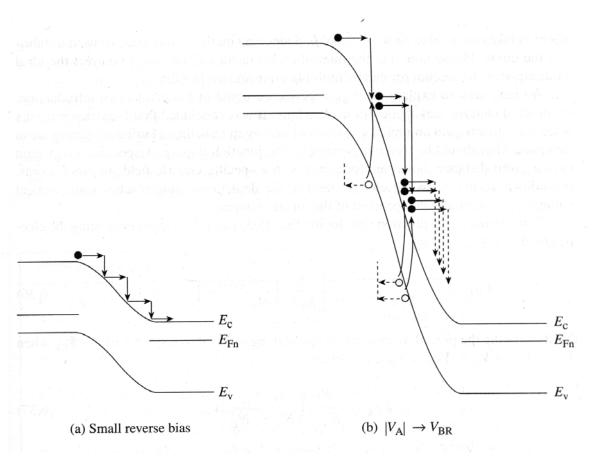
- Reverse "Breakdown" characteristics
 - •"Breakdown" is a deceptive term because no damage typically occurs to the device. Often diodes are designed to operate in the breakdown mode.

Breakdown Mechanisms

Avalanche Breakdown:

Excess current flows due to electron-hole pair multiplication due to impact ionization. This current rapidly increases with increasing reverse bias.

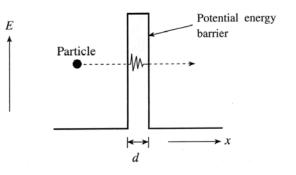




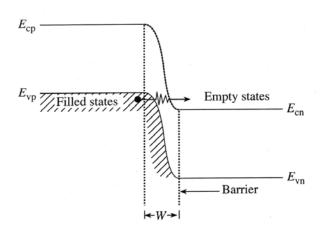
Breakdown Mechanisms

Zener Breakdown:

Excess current flows due to bonding electrons "tunneling" into empty conduction band states. The "tunneling barrier" must be sufficiently thin. This current rapidly increases with increasing reverse bias.







"Zener" Diodes

Zener diodes may actually operate based on either avalanche or zener breakdown mechanisms.

Rule of thumb: $|V_{BR}| > 6E_G/q$ is typically Avalanche Breakdown

